

Search Notes

Application/Control No.

10/667,364

Examiner

Gopal C. Ray

Applicant(s)/Patent under Reexamination

WON, JONG-EUN

Art Unit

2111

SEARCHED

Class	Subclass	Date	Examiner
710	301- 304,100,6 2,2,74	7/1/2005	GCR
713	400	7/1/2005	GCR
326	8	7/1/2005	GCR
714	5,7	7/1/2005	GCR
711	115	7/5/2005	GCR
361	684,685	7/5/2005	GCR

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
WEST: USPT, US OCR, EPO ABS, JPO ABS, DWPI, IBM TDB	7/1/2005	GCR
EAST: USPT	7/1/2005	GCR
NPL: IEEE Xplore	7/1/2005	GCR